



**MICROCHIP**

## **QUALIFICATION PLAN SUMMARY**

**PCN #: CENO-08SGWI805**

**Date:**

**February 12, 2026**

**Qualification of MMT as a new final test and MTAI as a new scan and pack site for SG3503M, SG3503DM-TR, SG3503DM catalog part numbers (CPN) available in 8L SOIC (.150in) and 8L PDIP (.300in) package.**

**The SG3526DW, SG2526DW, SG3526DW-TR, SG3526N and SG2526N catalog part numbers (CPN) available in 18L SOIC (.300in) and 18L PDIP (.300in) packages will qualify by similarity (QBS).**



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**Purpose:** Qualification of MMT as a new final test and MTAI as a new scan and pack site for SG3503M, SG3503DM-TR, SG3503DM catalog part numbers (CPN) available in 8L SOIC (.150in) and 8L PDIP (.300in) package. The SG3526DW, SG2526DW, SG3526DW-TR, SG3526N and SG2526N catalog part numbers (CPN) available in 18L SOIC (.300in) and 18L PDIP (.300in) packages will qualify by similarity (QBS).

**CCB No.:** 8030 and 8030.004

Test Name	Test Conditions	Sample Size	Qty of Lots	Fail/Accept Criteria
Bin and Yield Comparison	Test the same units at existing and destination locations and compare Bin and Yield data.	33	1	≤0.1%
Parametric / Characterization Comparison	Characterize the same units at existing and destination locations and compare data.	33	1	≤10.0%
Correlation Lot Report	Yield at each step and reject analysis between systems. 33 units are tested as lot correlation.	33	1	≤0.1%